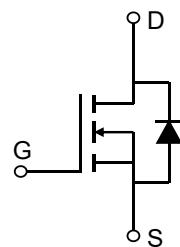


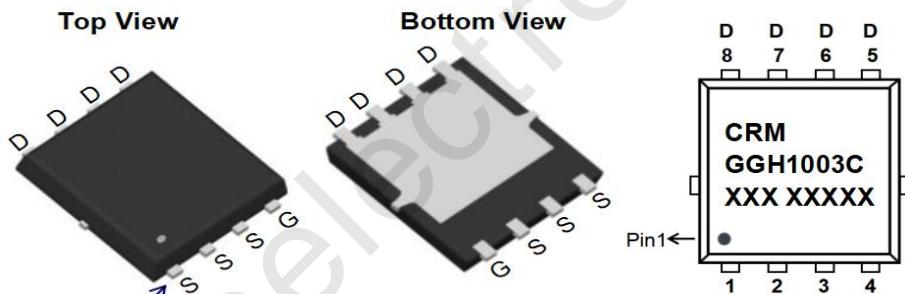
Description

Features

- 100V, 138A
- $R_{DS(ON)}$ Typ = 3mΩ @ V_{GS} = 10V
- Advanced Split Gate Trench Technology
- Excellent $R_{DS(ON)}$ and Low Gate Charge
- 100% UIS TESTED!
- 100% ΔV_{ds} TESTED!



Schematic Diagram



Marking and Pin Assignment

Package Marking and Ordering Information

Device	Marking	Package	Outline	Reel Size	Reel (pcs)	Per Carton (pcs)
CRMGGH1003C	CRMGGH1003C	PDFN5x6-8L	TAPING	13"	5000	60000

Absolute Maximum Ratings (@ T_J = 25°C unless otherwise specified)

Symbol	Parameter	Value	Units
V_{DS}	Drain-to-Source Voltage	100	V
V_{GS}	Gate-to-Source Voltage	±20	V
I_D	Continuous Drain Current $T_C = 25^\circ\text{C}$	138	A
		$T_C = 100^\circ\text{C}$	A
I_{DM}	Pulsed Drain Current ⁽¹⁾	552	A
E_{AS}	Single Pulsed Avalanche Energy ⁽²⁾	342	mJ
P_D	Power Dissipation $T_C = 25^\circ\text{C}$	139	W
$R_{θJC}$	Thermal Resistance, Junction to Case	0.9	°C/W
T_J, T_{STG}	Junction & Storage Temperature Range	-55 to 150	°C

Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}$	100	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 100\text{V}, V_{GS} = 0\text{V}$	-	-	1.0	μA
I_{GSS}	Gate-Body Leakage Current	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	2.4	2.7	3.6	V
$R_{\text{DS(ON)}}$	Static Drain-Source ON-Resistance ⁽³⁾	$V_{GS} = 10\text{V}, I_D = 30\text{A}$	-	3	3.9	$\text{m}\Omega$
Dynamic Characteristics						
C_{iss}	Input Capacitance		-	3658	-	pF
C_{oss}	Output Capacitance	$V_{GS} = 0\text{V}, V_{DS} = 50\text{V}, f = 1\text{MHz}$	-	1536	-	pF
C_{rss}	Reverse Transfer Capacitance		-	19	-	pF
Q_g	Total Gate Charge		-	49	-	nC
Q_{gs}	Gate Source Charge	$V_{GS} = 0$ to 10V	-	17	-	nC
Q_{gd}	Gate Drain("Miller") Charge	$V_{DS} = 50\text{V}, I_D = 20\text{A}$	-	6	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-On DelayTime		-	26	-	ns
t_r	Turn-On Rise Time	$V_{GS} = 10\text{V}, V_{DD} = 50\text{V}$	-	15	-	ns
$t_{d(off)}$	Turn-Off DelayTime	$I_D = 48\text{A}, R_{\text{GEN}} = 6\Omega$	-	28	-	ns
t_f	Turn-Off Fall Time		-	12	-	ns
Drain-Source Diode Characteristics and Max Ratings						
I_S	Maximum Continuous Drain to Source Diode Forward Current		-	-	138	A
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	552	A
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS} = 0\text{V}, I_S = 30\text{A}$	-	-	1.2	V
trr	Body Diode Reverse Recovery Time		-	60	-	ns
Qrr	Body Diode Reverse Recovery Charge	$I_F = 24\text{A}, di/dt = 100\text{A/us}$	-	70	-	nC

Notes:

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

2. E_{AS} condition: Starting $T_J=25^\circ\text{C}$, $V_{DD}=50\text{V}$, $V_G=10\text{V}$, $R_G=25\text{ohm}$, $L=0.5\text{mH}$, $I_{AS}=37\text{A}$

3. Pulse Test: Pulse Width $\leqslant 300\mu\text{s}$, Duty Cycle $\leqslant 0.5\%$.

Test Circuit

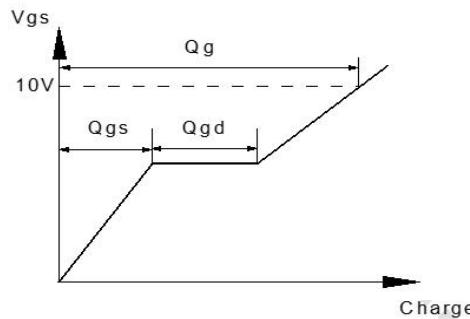
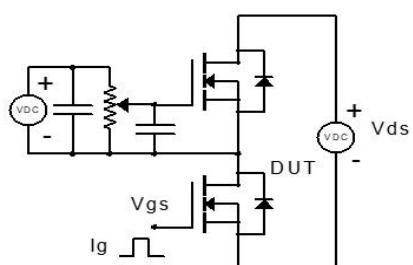


Figure 1: Gate Charge Test Circuit & Waveform

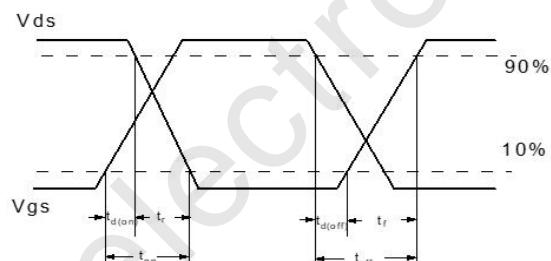
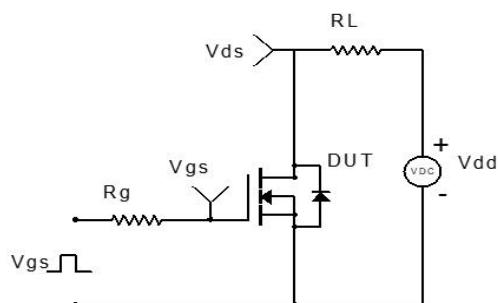


Figure 2: Resistive Switching Test Circuit & Waveform

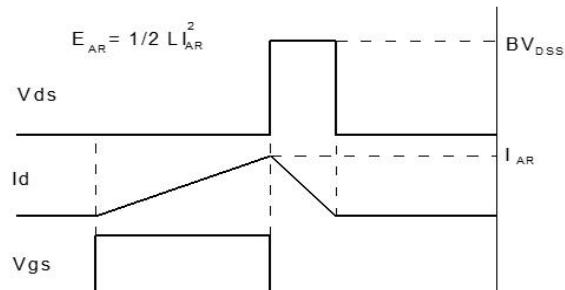
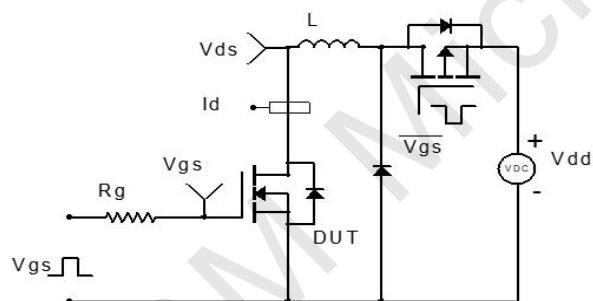


Figure 3: Unclamped Inductive Switching Test Circuit & Waveform

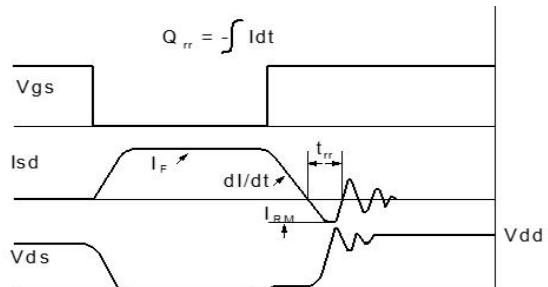
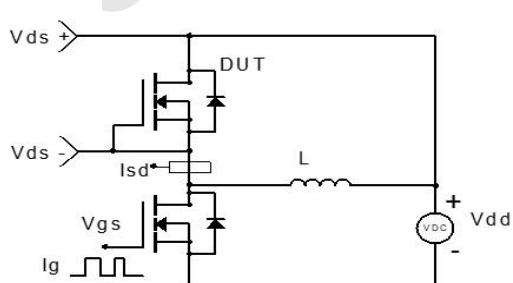
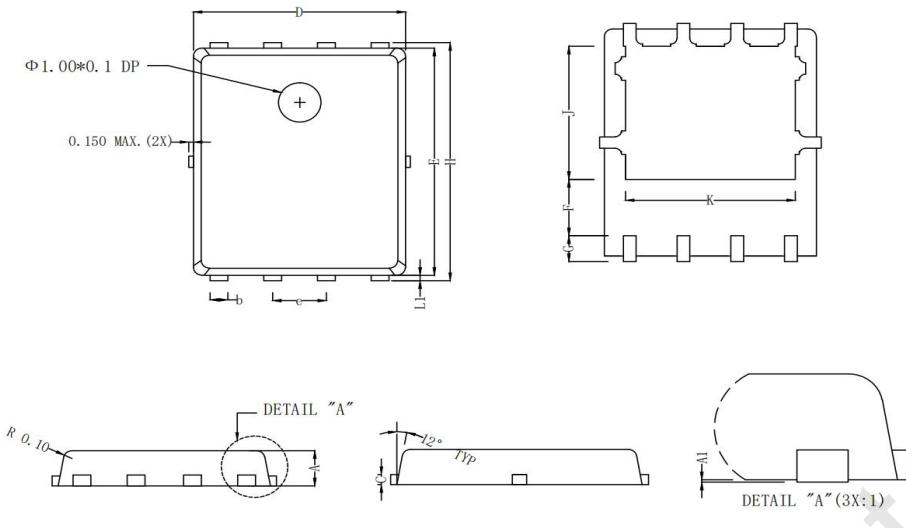


Figure 4: Diode Recovery Test Circuit & Waveform

Package Mechanical Data(PDFN5x6-8L)



Dimensions In Millimeterer			
Symbol	MIN	TYP	MAX
A	0.90	1.00	1.10
A1	0.00	0.03	0.05
b	0.25	0.30	0.35
c	0.254	REF	
D	4.80	4.90	5.00
F	1.35	REF	
E	5.65	5.75	5.85
e	1.27	BSC	
H	5.90	6.00	6.10
L1	0.10	0.13	0.16
G	0.55	REF	
K	4.00	REF	
J	3.45	REF	

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Contact information

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